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	Filing Date		2005-09-30	
	First Named Inventor	LEACH, et al.		
	Art Unit	3737		
	Examiner Name	Unknown		
Attorney Docket Number		Unknown		

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	1	5099208		1992-03-24	FITZPATRICK, et al.	

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1	REINSBERG, SA, et al., "Mutual information-based correction of BO inhomogeneity, susceptibility-and chemical-shift artefacts", Proceedings of the International Society for Magnetic Resonance in Medicine, 11th Scientific Meeting and Exhibition, Toronto, Canada, 10-16 July 2003, 10 July 2003, page 1049. XP002479792. SA, <input type="checkbox"/>
2	DONG, S. et al., "Rectification of distortion in MRI for stereotaxy", "MRI Distortion and Rectification", "Experiments", Proceedings of the Annual Symposium on Computer Based Medical Systems, Durham, June 14-17, 1992, New York, IEEE D. US, vol. SYMP. 5, 14 June 1992, pages 181-189. XPO10028189 <input type="checkbox"/>
3	HAACKE, EM, et al., "Magnetic resonance imaging - physical principles and sequence design", 1999, John Wiley & Sons, Inc., New York, pages 803-804, figure 26.17. XP002287202 <input type="checkbox"/>
4	WEISKOPF, N., et al., "Correction of geometric distortion in FMRI: A single-shot technique using multi-echo echo-planar imaging (EPI)", Proceedings of the International Society for Magnetic Resonance in Medicine, 11th Scientific Meeting and Exhibition, Toronto, Canada, 10-16 July 2003, 10 July 2003, page 1742. XP002287244 <input type="checkbox"/>
5	STEFAN A REINSBERG, et al., "A complete distortion correction for MR images: II. Rectification of static-field inhomogeneities by similarity-based profile mapping; BO correction of MR images", Physics in Medicine and Biology, Taylor and Francis Ltd. London, GB, vol. 50, no. 11, 7 June 2005, pages 2651-2661. XP020084220 <input type="checkbox"/>
6	SIMON J. DORAN, et al., "A complete distortion correction for MR images" I. Gradient warp correction; Gradient warp correction of MR images", Physics in Medicine and Biology, Taylor and Francis Ltd. London, GB, vol. 50, no. 7, 7 April 2005, pages 1343-1361. XP020084555 <input type="checkbox"/>
7	EP 08003252.7-2209 (European Search Report dated 06/06/2008). <input type="checkbox"/>

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